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Fullerton et al.

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(54) **FIELD EMISSION SYSTEM AND METHOD**

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(51) **Int. Cl.**

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335/302–306; 24/303; 310/90.5; 2/102–103,
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See application file for complete search history.

(57) **ABSTRACT**

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An improved field emission system and method is provided
that involves field emission structures having electric or mag-
netic field sources. The magnitudes, polarities, and positions
of the magnetic or electric field sources are configured to have
desirable correlation properties, which may be in accordance
with a code. The correlation properties correspond to a
desired spatial force function where spatial forces between
field emission structures correspond to relative alignment,
separation distance, and the spatial force function.

23 Claims, 45 Drawing Sheets

